

AFRL-RZ-WP-TP-2012-0122

SM AND ND SUBSTITUTIONS IN YBCO FILMS PRODUCED THROUGH METAL ORGANIC DEPOSITION (POSTPRINT)

B.C. Harrison, J. Carpenter, P. Klenk, and P.N. Barnes

Mechanical Energy Conversion Branch Energy/Power/Thermal Division

H. Fang

University of Houston

C.V. Varanasi

University of Dayton Research Institute

FEBRUARY 2012

Approved for public release; distribution unlimited.

See additional restrictions described on inside pages

STINFO COPY

© 2006 American Institute of Physics

AIR FORCE RESEARCH LABORATORY
PROPULSION DIRECTORATE
WRIGHT-PATTERSON AIR FORCE BASE, OH 45433-7251
AIR FORCE MATERIEL COMMAND
UNITED STATES AIR FORCE

REPORT DOCUMENTATION PAGE

2. REPORT TYPE

Form Approved OMB No. 0704-0188

3. DATES COVERED (From - To)

The public reporting burden for this collection of information is estimated to average 1 hour per response, including the time for reviewing instructions, searching existing data sources, gathering and maintaining the data needed, and completing and reviewing the collection of information. Send comments regarding this burden estimate or any other aspect of this collection of information, including suggestions for reducing this burden, to Department of Defense, Washington Headquarters Services, Directorate for Information Operations and Reports (0704-0188), 1215 Jefferson Davis Highway, Suite 1204, Arlington, VA 22202-4302. Respondents should be aware that notwithstanding any other provision of law, no person shall be subject to any penalty for failing to comply with a collection of information if it does not display a currently valid OMB control number. PLEASE DO NOT RETURN YOUR FORM TO THE ABOVE ADDRESS.

February 2012	Conference Paper Postprint 01 Janua		ary 2004 – 01 January 2006			
4. TITLE AND SUBTITLE SM AND ND SUBSTITUTIONS II	5a. CONTRACT NUMBER In-house					
ORGANIC DEPOSITION (POSTP	5b. GRANT NUMBER					
	5c. PROGRAM ELEMENT NUMBER 62203F					
6. AUTHOR(S)	5d. PROJECT NUMBER					
B.C. Harrison, J. Carpenter, P. Klen	3145					
H. Fang (University of Houston)	5e. TASK NUMBER					
C.V. Varanasi (University of Dayto	32					
	5f. WORK UNIT NUMBER 314532ZE					
7. PERFORMING ORGANIZATION NAME(S) AN	ND ADDRESS(ES)			8. PERFORMING ORGANIZATION		
Mechanical Energy Conversion Branch (AFI Energy/Power/Thermal Division Air Force Research Laboratory, Propulsion I	Directorate	University of Houston Department of Mechanical Houston, TX 77204	Engineering	REPORT NUMBER AFRL-RZ-WP-TP-2012-0122		
Wright-Patterson Air Force Base, OH 45433 Air Force Materiel Command United States Air Force	3-7251	University of Dayton Resea 300 College Park Dayton, OH 45469	arch Institute			
9. SPONSORING/MONITORING AGENCY NAM		10. SPONSORING/MONITORING				
Air Force Research Laboratory Propulsion Directorate	AGENCY ACRONYM(S) AFRL/RZPG					
Wright-Patterson Air Force Base, C Air Force Materiel Command United States Air Force	11. SPONSORING/MONITORING AGENCY REPORT NUMBER(S) AFRL-RZ-WP-TP-2012-0122					
12. DISTRIBUTION/AVAILABILITY STATEMENT Approved for public release; distribution unlimited.						
13. SUPPLEMENTARY NOTES Conference paper published in the proc Cryogenic Materials Conference, Vol. © 2006 American Institute of Physics. release, perform, display, or disclose th PA Case Number: AFRL/WS 06-0223;	52, 2006. This c The U.S. Govern e work. Work on	onference was held in Keyston ment is joint author of the want this effort was completed in	one, CO, 29 Atork and has th	agust through 02 September 2005. e right to use, modify, reproduce,		

14. ABSTRACT

1. REPORT DATE (DD-MM-YY)

Epitaxial YBa₂Cu₃O_{7-x} (YBCO) films were produced on non-buffered (100) single crystal LaAlO₃ using the metal organic deposition (MOD) method with fluorinated metal acetates. In an effort to enhance the in-field performance of the films, Sm and Nd acetates were fractionally substituted for Y acetate in a series of precursor solutions to incorporate an array of nanoscale flux pinning centers in the post-annealed films. From measurements taken in the non-optimized films a 50%-150% improvement in critical current density at 77K in fields up to IT were found for films with a 1/3 substitution of the Rare Earth elements, with farther improvements at 40K. Furthermore, a study of the microstructure of the films by scanning electron microscopy (SEM) reveals the presence of nanoparticles on the surfaces of the films.

15. SUBJECT TERMS

non-buffered, post-annealed, non-optimized, microstructure, scanning electron microscopy, nanoscale flux pinning centers

16. SECURITY CLASSIFICATION OF:		17. LIMITATION	18. NUMBER	19a. NAME OF RESPONSIBLE PERSON (Monitor)	
··-·		c. THIS PAGE Unclassified	OF ABSTRACT: SAR	OF PAGES 12	Timothy J. Haugan 19b. TELEPHONE NUMBER (Include Area Code) N/A

SM AND ND SUBSTITUTIONS IN YBCO FILMS PRODUCED THROUGH METAL ORGANIC DEPOSITION

B.C. Harrison¹, H. Fang², J. Carpenter¹, P. Klenk¹, C. V. Varanasi³, P. N. Barnes¹

¹Air Force Research Laboratory WPAFB, OH, 45433, USA

²University of Houston, Department of Mechanical Engineering Houston, TX, 77204, USA

³University of Dayton Research Institute, 300 College Park, Dayton, OH, 45469, USA

ABSTRACT

Epitaxial YBa₂Cu₃O_{7-X} (YBCO) films were produced on non-buffered (100) single crystal LaAlO₃ using the metal organic deposition (MOD) method with fluorinated metal acetates. In an effort to enhance the in-field performance of the films, Sm and Nd acetates were fractionally substituted for Y acetate in a series of precursor solutions to incorporate an array of nanoscale flux pinning centers in the post-annealed films. From measurements taken in the non-optimized films a 50%-150% improvement in critical current density at 77K in fields up to 1T were found for films with a 1/3 substitution of the Rare Earth elements, with further improvements at 40K. Furthermore, a study of the microstructure of the films by scanning electron microscopy (SEM) reveals the presence of nanoparticles on the surfaces of the films.

KEYWORDS: MOD, Metal Organic Deposition, YBCO, Sm, Nd, substitution, Rare Earth **PACS:** 74.62.Dh, 74.78.Bz, 74.72.Bk

INTRODUCTION

Second generation high-temperature superconductor (HTS) wire is based on an epitaxial YBCO film grown on a biaxially textured substrate. A primary concern in the development of second-generation HTS wire is choosing a cost-effective manufacturing process that maintains the high electrical performance obtained by laboratory methods.

1

Approved for public release; distribution unlimited

This requires the minimization of initial capital investments and ongoing processing costs while maintaining the performance required for practical applications.

The Trifluroacetate-Metal Organic Deposition (TFA-MOD) process is being used in the scale up of coated conductor production, since it provides a low cost solution with the added benefits of high production rate, no vacuum equipment requirements, large scale film uniformity, and high critical current densities[1]. However, in order to be utilized in the full spectrum of power applications, such as generators, transformers, etc... the in-field performance of the HTS films must be enhanced. One method of achieving this enhancement is to incorporate nanoscale defects into the microstructure to act as magnetic flux pinning centers that create a potential barrier to flux flow. Although these defects have been investigated in films produced by Pulsed Laser Deposition (PLD), significantly less has appeared in the literature for MOD derived films[2,3]. Furthermore, techniques used to incorporate nanoparticles in PLD may not transfer over to MOD, due to the differences in the growth mechanisms and processing environments. In this initial report of an investigation to determine the optimal method of enhancing the in-field performance of TFA-MOD YBCO the most straight-forward method of introducing pinning centers into the film is addressed; that of Rare Earth elemental substitution for Y. It was previously demonstrated that that by substituting Yttrium by other RE elements, the in-field properties could be dramatically improved [4,5,6] due to stress field induced flux pinning.

Compared to other deposition methods, it may be simpler to incorporate RE elements for Y substitution using MOD. Only the replacement of a portion of the Y acetate by one or more RE acetates is needed in the preparation of the precursor solution. Furthermore, due to the similar chemical properties of the metal ions and sizes of the superconducting lattice unit cells, substitution does lead to large degradation in the film, but can still produce pinning centers. In this portion of the study the RE elements of Sm and Nd were substituted for Y. The lattice mismatch of the SmBCO and NdBCO unit cells in comparison to YBCO are a= -0.41%, b= -0.34%, c= -0.29% and a= -0.40%, b= -0.34%, c= -0.34%, respectively; thus producing tensile stress when incorporated into a YBCO lattice and possibly leading to phase separation.

EXPERIMENTAL

The YBCO precursor solution was prepared by dissolving amounts of Y, Sm, Nd, Ba, and Cu acetates in TFA according to a stiochiometric ratio of $Y_{1-X}RE_XBa_2Cu_3$ where RE=Sm or Nd and $X=\frac{1}{3}$, $\frac{2}{3}$ or 1. The solution was refluxed for 4 hours and subsequently heated to remove TFA. To remove traces of TFA, water and acetic acid the purifying method suggested by Araki et al. was used [7]. Thus, the resulting gel was dissolved in methanol and refluxed several times at 323K. The purified gel was dissolved in methanol to attain a final solution concentration of 0.25M. The precursor solution was deposited on LaAlO₃ <100> substrates. Excess solution was removed by spinning the films at 4000rpm for 120s in air. The samples were heat treated with a schedule similar to the one reported by Y.-A. Jee et al. [8].

Samples where analyzed to determine the texture and microstructure. The texture was analyzed using X-ray diffraction and the microstructure was characterized utilizing SEM. A Rigaku coupled 2θ goniometer along with a Phillips Materials Research Diffractometer utilizing CuK α 1 radiation were used to obtain 2θ scans. The 2θ scans were taken between 10° and 120° with a step size of 0.05° and a scan rate of 6° /min. The SEM used for surface imaging is a Sirion microscope made by FEI.

RESULTS

Figures 1 and 2 display the X-ray diffraction patterns of $Y_{1-X}Nd_XBa_2Cu_3O_{7-Y}$ and $Y_{1-X}Sm_XBa_2Cu_3O_{7-Y}$ where X=0, $\frac{1}{3}$, $\frac{2}{3}$ and 1. Only the (00*l*) peaks appear in the RE substituted films and are located at the same positions as those of YBCO. This shows the successful growth of the substituted textured films and is supported by measured T_{Conset} values of ~92K and transition widths of 2-4K for YBCO and RE substituted samples. The intensity of the peaks decrease with the addition of Nd or Sm, which implies that the crystallinity or unit cell structures are changing with increased dopant concentration. It must be noted that these films were processed using parameters developed for YBCO. They are therefore not optimized and it is possible that under different conditions less change would be observed. In particular use of a higher temperature during the conversion process might provide a significant improvement in crystallinity; since NdBCO and SmBCO both have a higher formation temperature than YBCO.

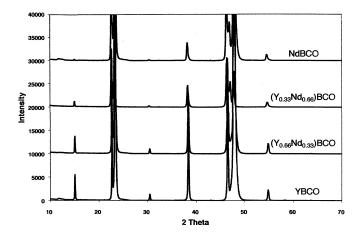


FIGURE 1. X-ray diffraction patterns for $Y_{1-X}Nd_XBa_2Cu_3O_{7-Y}$ where $X=0, \frac{1}{3}, \frac{2}{3}$ and 1.

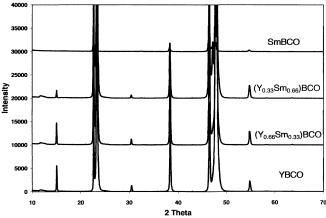


FIGURE 2. X-ray diffraction patterns for $Y_{1-X}Sm_XBa_2Cu_3O_{7-Y}$ where $X=0, \frac{1}{3}, \frac{2}{3}$ and 1.

Figures 3 and 4 display the in-field critical current density of several Sm and Nd doped films compared to YBCO at 77K and 40K, respectively. The in-field critical current is significantly improved by the $\frac{1}{2}$ substitutions of Sm and Nd. At 77K in fields up to 1T 50%-150% improvements in critical current density were found for these films. While the Sm_{0.33} curve remains nearly constant in relation to YBCO at 40K, the Nd_{0.33} curve exhibits a further improvement in performance. At 40K the Nd_{0.33} film has a critical current density \geq 100% larger than YBCO up to 4T, \geq 50% larger up to 8T and some level of improvement up to 10T. Only the Sm_{0.66} sample shows deterioration in the film quality. At 77K the entire curve of J_C is below that of YBCO and shows such a large negative slope that at 1.5T J_C is only 15% of the YBCO value. At 40K there is some improvement at fields less than 4.5T, however at that field density there is a crossover and the performance is degraded at higher fields. These results call for a more detailed investigation of substitutions around 33% and lower concentrations in order to determine an optimal doping level.

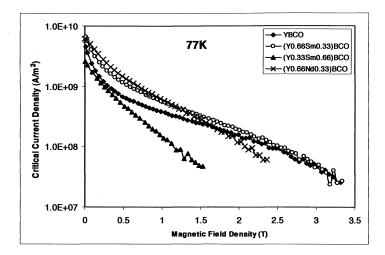


FIGURE 3. In-field critical current density of films at 77K.

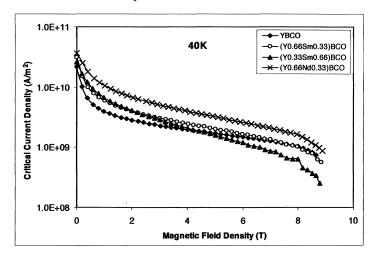
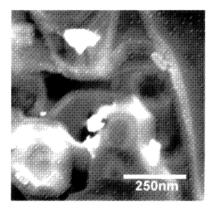


FIGURE 4. In-field critical current density of films at 40K.



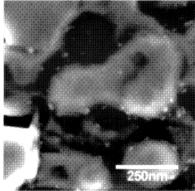


FIGURE 5. SEM pictures of the $Y_{0.66}Nd_{0.33}Ba_2Cu_3O_{7-Y}$ (left) and $Y_{0.66}Sm_{0.33}Ba_2Cu_3O_{7-Y}$ (right).

SEM images of the $Y_{0.66}Nd_{0.33}Ba_2Cu_3O_{7-Y}$ and $Y_{0.66}Sm_{0.33}Ba_2Cu_3O_{7-Y}$ films are shown in Figure 5. Nanoparticles less than 10nm wide are present on both of the substituted films. These particles are not observed on pure YBCO film. On the $Nd_{0.33}$ film the particles are randomly, uniformly arrayed, while on the $Sm_{0.33}$ film, the nanoparticles decorate the grain boundaries. Although a cross-sectional TEM analysis would be needed to confirm the presence of nanoparticles inside the films, the surface particles suggests that phase separation has occurred for both RE substitutions.

CONCLUSIONS

This initial report of a study on the optimization of in-field properties of second generation HTS wire produced by MOD reveals a significant improvement of the critical current density of YBCO films by the fractional substitution of the RE elements Nd and Sm for Y. Additionally, the nanoparticles on the surface of the films suggest that the improvement may be due to the presence of particulate pinning centers within the films brought about by phase separation. In higher quality films these nanoparticles are anticipated to likewise improve the in-field performance; however, in order to verify these results the baseline YBCO film quality must be further improved and the proper processing parameters determined for the substituted films.

REFERENCES

- 1. A. P. Malozemoff, "Second Generation HTS Wire: An Assessment", American Superconductor White Paper, July (2004)
- 2. A. Kaneko, J. Matsuda, R. Teranishi, K. Nakaoka, Y. Aoki, H. Fuji, K. Murata, T. Goto, A. Yoshinaka, A. Yajima, T. Izumi, Y. Shiohara, *Physica C*, **426-431**, pp. 949-953 (2005)
- 3. U. Schoop, M. W. Rupich, C. Thieme, D. T. Verebelyi, W. Zhang, X. Li, T. Kodenkandath, N. Nguyen, E. Siegal, L. Civale, T. Holesinger, B. Maiorov, A. Goyal, P. Paranthaman, *IEEE Trans. Appl. Supercoduc.*, **15**, pp. 2611-2616 (2005)
- C. Cai, B. Holzapfel, J. Hanisch, L. Fernandez, L. Schultz, Phys. Rev. B, 69, pp. 104531-104534 (2004).
- 5. J. L. MacManus-Driscoll, S. R. Foltyn, Q. X. Jia, H. Wang, A. Serquis, B. Maiorov, L. Civale, Y. Lin, M. F. Hawley, M. P. Maley, D. F. Peterson, April Phys. Lett. 84, pp. 5329-5331 (2004).
- M. E. Hawley, M. P. Maley, D. E. Peterson, Appl. Phys. Lett., 84, pp. 5329-5331 (2004)
- 6. J. W. Kell, T. J. Haugan, M. F. Locke, P. N. Barnes, *IEEE Trans. Appl. Supercoduc.*, **15**, pp. 3726-3729 (2005)

- T. Araki, I. Hirabayashi, Supercond. Sci. Technol., 16, pp. 7-11 (2001).
 Y.-A. Jee, M.Li, B. Ma, V. A. Maroni, B. L. Fisher, U. Balachandran, *Physica C*, 356, pp. 297-303 (2001).